

60V N-Channel Enhancement Mode MOSFET

Description

The AP50N06P/T uses advanced trench technology

to provide excellent $R_{\text{DS}(\text{ON})},$ low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

General Features

V_{DS} = 60V I_D =50 A

 $R_{DS(ON)} < 15m\Omega @ V_{GS}=10V$

Application

Battery protection

Load switch

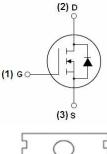
Uninterruptible power supply

Package Marking and Ordering Information

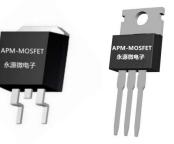
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Product ID	Pack	Marking	Qty(PCS)
AP50N06P	TO-220-3L	AP50N06P XXXX YYYY	1000
AP50N06T	TO-263-3L	AP50N06T XXXX YYYY	1000

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
Vds	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
I₀@Tc=25°C	Continuous Drain Current, V _{GS} @ 10V ¹	50	А
I₀@Tc=100°C	Continuous Drain Current, V _{GS} @ 10V ¹	34	А
Ідм	Pulsed Drain Current ²	100	А
EAS	Single Pulse Avalanche Energy ³	40	mJ
las	Avalanche Current	28	А
P₀@Tc=25°C	Total Power Dissipation ⁴	74	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Reja	Thermal Resistance Junction-Ambient ¹	62	°C/W
Rejc	Thermal Resistance Junction-Case ¹	1.68	°C/W









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Electrical Characteristics (TJ=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	60			V
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =20A		13.5	20	mΩ
VGS(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.2		2.5	V
		V _{DS} =48V , V _{GS} =0V , T _J =25°C			1	uA
IDSS	Drain-Source Leakage Current	V _{DS} =48V , V _{GS} =0V , T _J =55°C			5	
IGSS Gate-Source Leakage Current		V _{GS} =±20V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =20A		25		S
Qg	Total Gate Charge (4.5V)	V _{DS} =48V , V _{GS} =4.5V , I _D =15A		19.3		nC
Qgs	Gate-Source Charge			7.1		
Qgd	Gate-Drain Charge			7.6		
Td(on)	Turn-On Delay Time			7.2		ns
Tr	Rise Time			50		
Td(off)	Turn-Off Delay Time			36.4		
T _f	Fall Time			7.6		
Ciss	Input Capacitance			2423		pF
Coss	Output Capacitance	− V _{DS} =15V , V _{GS} =0V , f=1MHz		145		
Crss	Reverse Transfer Capacitance			97		
ls	Continuous Source Current ^{1,5}	$V_G=V_D=0V$, Force Current			45	А
Vsd	Diode Forward Voltage ²	V _{GS} =0V , I _S =A , T _J =25°C			1	V
trr	Reverse Recovery Time	IF=15A , dI/dt=100A/µs ,		16.3		nS
Q _{rr}	Q _{rr} Reverse Recovery Charge			11		nC

Note :

1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width \leqq 300us , duty cycle \leqq 2%

3.The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=28A

4.The power dissipation is limited by 150°C junction temperature

5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

N



Typical Characteristics

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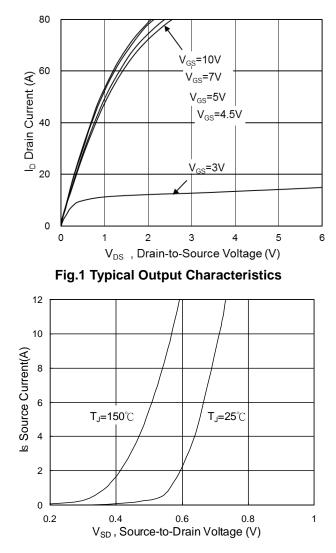


Fig.3 Forward Characteristics of Reverse

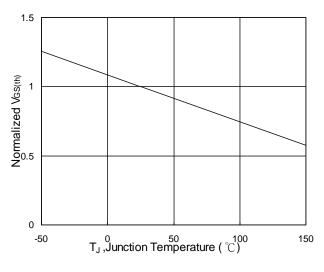


Fig.5 Normalized $V_{GS(th)}$ vs T_J

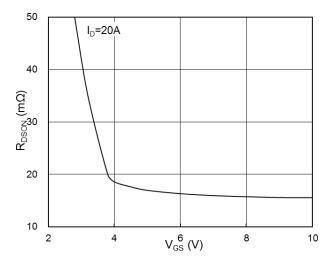


Fig.2 On-Resistance vs Gate-Source Voltage

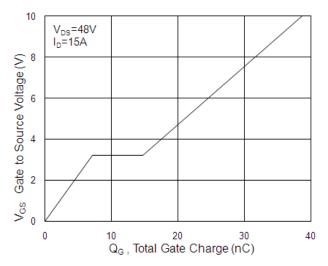
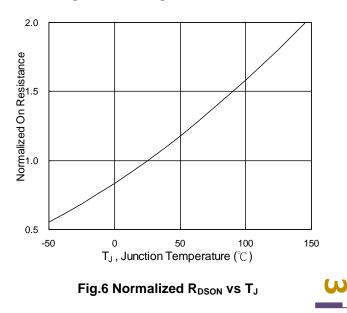
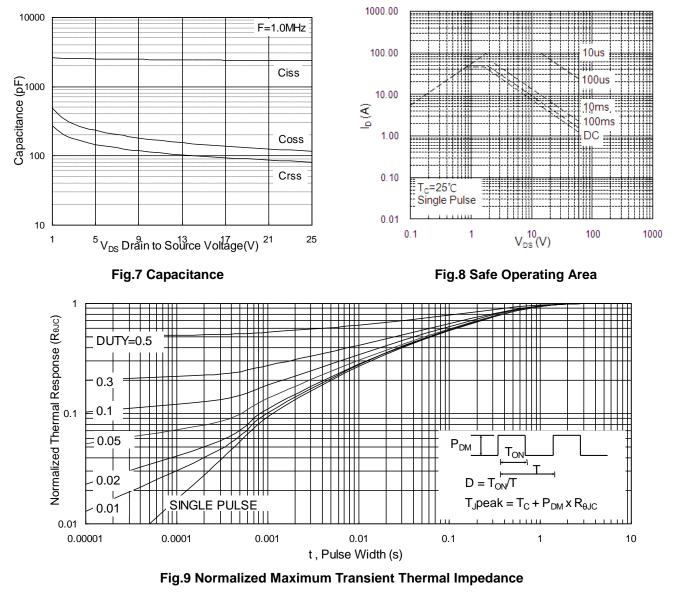


Fig.4 Gate-Charge Characteristics





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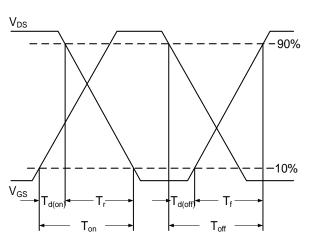


Fig.10 Switching Time Waveform

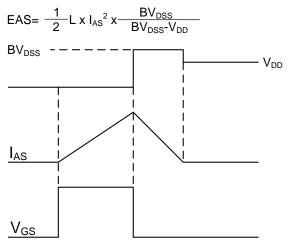
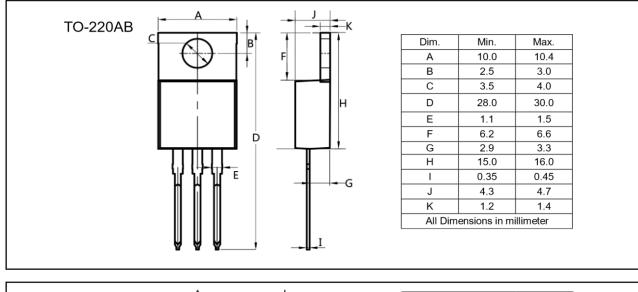
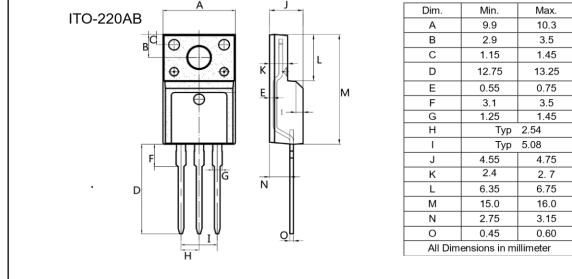


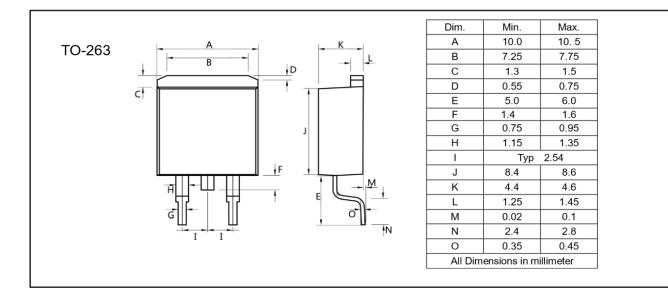
Fig.11 Unclamped Inductive Switching Waveform



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